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ICS 31.200
CCS L56

SJ

# INDUSTRY STANDARD OF THE PEOPLE'S REPUBLIC OF CHINA

# SJ 21550-2020

## High-speed signal transmission performance test method of microelectronic package ceramic housing

微电子封装陶瓷外壳高速信号传输性能测试方法

**(English Translation)**

**Implemented on: August 1, 2020**

**Issued by: Ministry of Industry and Information Technology**

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https://chinastandards.org/standards/sj-21550-2020

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## 1 Foreword

SJ 21550-2020 was issued by Ministry of Industry and Information Technology on 3 June 2020 and has been in force since 1 August 2020.

The SJ prefix, without a suffix, marks a mandatory standard: within its scope, compliance is required.

The document runs to 8 pages in English translation.

## 2 Scope Preview

SJ 21550-2020 falls under ICS 31.200, in the field of electronics.

This catalogue holds 133 other SJ standards in that field.

In this catalogue, SJ standards carry edition years from 1965 to 2021.



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## 3 About this standard

Sector: Electronics Industry Standard

Issued by: Ministry of Industry and Information Technology

English translation: about 8 pages (approximate)

Chinese original: about 10,155 characters

## 4 Related standards

Standards on related subjects:

SJ/T 11890-2023 - Design requirement of energy conservation for LED displays

SJ/T 11891-2023 - Energy efficiency measurement method for LED displays

GB/T 35010.6-2018 - Semiconductor die products -- Part 6: Requirements for concerning thermal simulation

SJ/T 12035-2025 - Artificial intelligence chip - Testing metrics and methods for edge-side deep learning chips

SJ/T 12034-2025 - Artificial intelligence chip - Testing metrics and methods for edge-side deep learning chips

SJ 21553-2020 - Three-dimensional heterogeneous integrated fine-pitch micro-bump production technology requirements

## 5 Classification and status

International classification (ICS): 31.200

Chinese Standard Classification (CCS): L 56

Prefix SJ: mandatory standard.



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